Ref #	Hits	Search Query	DBs	Default Operato r	Plural s	Time Stamp
L2	5	(US-20030196181-\$ or US-20060030914-\$).did. or (US-6484300-\$ or US-6189130-\$ or US-6845497-\$).did.	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:30
L3	3	2 and (copper)	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:30
L4	743	(73/32R).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:46
L5	837	702/108	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:47
L6	1318	702/117	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:47
L7	1654	702/189	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:47

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L8	416	702/23	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:47
L9	412	702/32	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:47
L10	1419	(716/6).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:47
L11	616	(716/7).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:48
L12	214	(716/15).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:48
L13	309	(716/20).CCLS.	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:49

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L14	7123	45678910111213	US-PGPU B; USPAT; USOCR; EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/14 15:49
S1	7	(("6066179") or ("6109775") or ("6189130") or ("6470482") or ("6484300") or ("6505325") or ("6513148")).PN.	US-PGPU B; USPAT; USOCR	OR	OFF	2006/02/15 16:12
S2	520	(73/32R).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/14 15:46
S3	209	S2 and (density)	US-PGPU B; USPAT	OR	OFF	2006/02/10 13:27
S4	751	702/108	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:47
S5	1169	702/117	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:47
S6	1447	702/189	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:47
S7	389	702/23	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:47
S8	388	702/32	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:47
S9	67	S4 and (density) and (PCB or board or circuit)	US-PGPU B; USPAT	OR	OFF	2006/02/10 13:30
S10	158	S5 and (density) and (PCB or board or circuit)	US-PGPU B; USPAT	OR	OFF	2006/02/10 14:15
S11	193	S6 and (density) and (PCB or board or circuit)	US-PGPU B; USPAT	OR	OFF	2006/02/10 14:18
S12	47	S7 and (density) and (PCB or board or circuit)	US-PGPU B; USPAT	OR	OFF	2006/02/10 14:23
S13	40	S8 and (density) and (PCB or board or circuit)	US-PGPU B; USPAT	OR	OFF	2006/02/10 14:30
S15	53	(density near4 (variation or variations or difference or differences)) same (circuit near4 board)	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/08 13:31

S16	8	("5528508" "6002857").PN. OR ("6189130").URPN.	US-PGPU B; USPAT; USOCR	OR	OFF	2006/02/10 14:56
S17	22	(density near4 (variation or variations or difference or differences)) same (circuit near4 board)	EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/07 16:30
S19	1299	(716/6).CCLS.	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:47
S20	558	(716/7).CCLS.	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:47
S21	199	S19 and (density)	US-PGPU B; USPAT	OR	OFF	2006/02/14 16:36
S22	137	S20 and (density)	US-PGPU B; USPAT	OR	OFF	2006/02/14 16:36
S23	199	(716/15).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/14 15:48
S24	71	S23 and (density)	US-PGPU B; USPAT	OR	OFF	2006/02/14 16:37
S25	106	((density) near4 (variation or variations or difference or differences)) same (modeling)	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:33
S27	21	(density near2 (variation or variance or variations)) near2 (analysis or analyze or analyzing)	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:34
S28	4	(density near2 (variation or variance or variations)) near10 (PCB or "printed circuit board" or "printed circuit boards")	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:35
S29	7	(density near2 (variation or variance or variations)) near2 (analysis or analyze or analyzing)	EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/07 16:35
S30	3	(density near2 (variation or variance or variations)) near10 (PCB or "printed circuit board" or "printed circuit boards")	EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/07 16:35

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S31	522	(73/32R).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/07 16:15
S32	830	702/108	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:16
533	1309	702/117	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:20
S34	1642	702/189	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:23
S35	414	702/23	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:26
S36	412	702/32	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:26
S37	712	(density near13 board) same (variation or variations or difference or differences)	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/07 16:29
S38	57	(density near4 (variation or variations or difference or differences)) same (circuit near4 board)	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/07 16:30
S39	22	(density near4 (variation or variations or difference or differences)) same (circuit near4 board)	EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/07 16:30
S40	1405	(716/6).CCLS.	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:31
S41	611	(716/7).CCLS.	US-PGPU B; USPAT	OR	OFF	2006/06/09 13:55
S42	212	(716/15).CCLS.	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/07 16:33
S43	114	((density) near4 (variation or variations or difference or differences)) same (modeling)	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:34
S44	22	(density near2 (variation or variance or variations)) near2 (analysis or analyze or analyzing)	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:34

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S45	5	(density near2 (variation or variance or variations)) near10 (PCB or "printed circuit board" or "printed circuit boards")	US-PGPU B; USPAT	OR	OFF	2006/06/07 16:35
S46	7	(density near2 (variation or variance or variations)) near2 (analysis or analyze or analyzing)	EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/07 16:35
S47	3	(density near2 (variation or variance or variations)) near10 (PCB or "printed circuit board" or "printed circuit boards")	EPO; JPO; DERWEN T; IBM_TDB	OR	OFF	2006/06/07 16:35
S48	35	(density near4 (variation or variations or difference or differences)) same (circuit near4 board) and ((multi near2 layer) or (multi near2 layered) or layers)	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/08 13:32
S50	326	(density near13 board) same (variation or variations or difference or differences) and ((multi near2 layer) or (multi near2 layered) or layers)	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/08 13:39
S51	311	S50 not S48	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/08 13:39
S52	326	(density near13 board) same (variation or variations or difference or differences) and ((multi near2 layer) or (multi near2 layered) or layers)	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/09 13:47
S53	713	(density near13 board) same (variation or variations or difference or differences)	US-PGPU B; USPAT; USOCR	OR	OFF	2006/06/09 13:48
S54	450	grid same layer\$4 same density same (board or pcb or circuit)	US-PGPU B; USPAT	OR	OFF	2006/06/09 13:51
S55	119	(grid with layer\$4) same density same (board or pcb or circuit)	US-PGPU B; USPAT	OR	OFF	2006/06/09 13:50
S56	308	(716/20).CCLS.	US-PGPU B; USPAT	OR	OFF	2006/06/14 15:48

S57	5	(US-20060030914-\$ or US-20030196181-\$).did. or (US-6484300-\$ or US-6189130-\$ or US-6845497-\$).did.	US-PGPU B; USPAT	OR	OFF	2006/06/09 15:26
S59	5	S57 and (layers)	US-PGPU B; USPAT	OR	OFF	2006/06/09 15:26

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C:\Documents and Settings\sshah2\My Documents\EAST\Workspaces\10609068 (measuring density variations on multi layer circuit boards)